

**Notice of References Cited**

Application/Control No.

09/630,454

Applicant(s)/Patent Under Reexam

Liaw Wt Al.

Examiner

S. Devi, Ph.D.

Art Unit

1645

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	US 4,346,170	08/24/82	Sano et al.	435	115
B	US 4,657,860	04/14/87	Nakanishi et al.	435	115
C	US 5,077,207	12/31/91	Shijo et al.	435	115
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages				
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<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.57  
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